

Application/Control No.	Applicant(s)/Patent under Reexamination
10/661,314	SHI ET AL.
Examiner	Art Unit
William I Deane	2614

SEARCHED					
Class	Subclass	Date	Examiner		
379	202.01				
	202.01				
	142.16				
	242				
	386				
	209.81				
	206.61				
	207.01				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

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